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Precision Analog Microcontroller, 12-Bit Analog I/O, ARM7TDMI MCU

Data Sheet

ADuC7019/20/21/22/24/25/26/27/28/29

FEATURES

Analog I/O
- Multichannel, 12-bit, 1 MSPS ADC
  - Up to 16 ADC channels[1]
- Fully differential and single-ended modes
- 0 V to V_{REF} analog input range
- 12-bit voltage output DACs
  - Up to 4 DAC outputs available[1]
- On-chip voltage reference
- On-chip temperature sensor (±3°C)
- Voltage comparator

Microcontroller
- ARM7TDMI core, 16-bit/32-bit RISC architecture
- JTAG port supports code download and debug

Clocking options
- Trimmed on-chip oscillator (±3%)
- External watch crystal
- External clock source up to 44 MHz
- 41.78 MHz PLL with programmable divider

Memory
- 62 kB Flash/EE memory, 8 kB SRAM
- In-circuit download, JTAG-based debug
- Software-triggered in-circuit reprogrammability

On-chip peripherals
- UART, 2× I²C® and SPI serial I/O
- Up to 40-pin GPIO port[1]
- 4× general-purpose timers
- Wake-up and watchdog timers (WDT)
- Power supply monitor
- 3-phase, 16-bit PWM generator[1]
- Programmable logic array (PLA)
- External memory interface, up to 512 kB[1]

Power
- Specified for 3 V operation
- Active mode: 11 mA @ 5 MHz, 40 mA @ 41.78 MHz

Packages and temperature range
- From 40-lead 6 mm × 6 mm LFCSP to 80-lead LQFP[1]
- Fully specified for −40°C to +125°C operation

Tools
- Low cost QuickStart™ development system
- Full third-party support

APPLICATIONS

Industrial control and automation systems
Smart sensors, precision instrumentation
Base station systems, optical networking

FUNCTIONAL BLOCK DIAGRAM

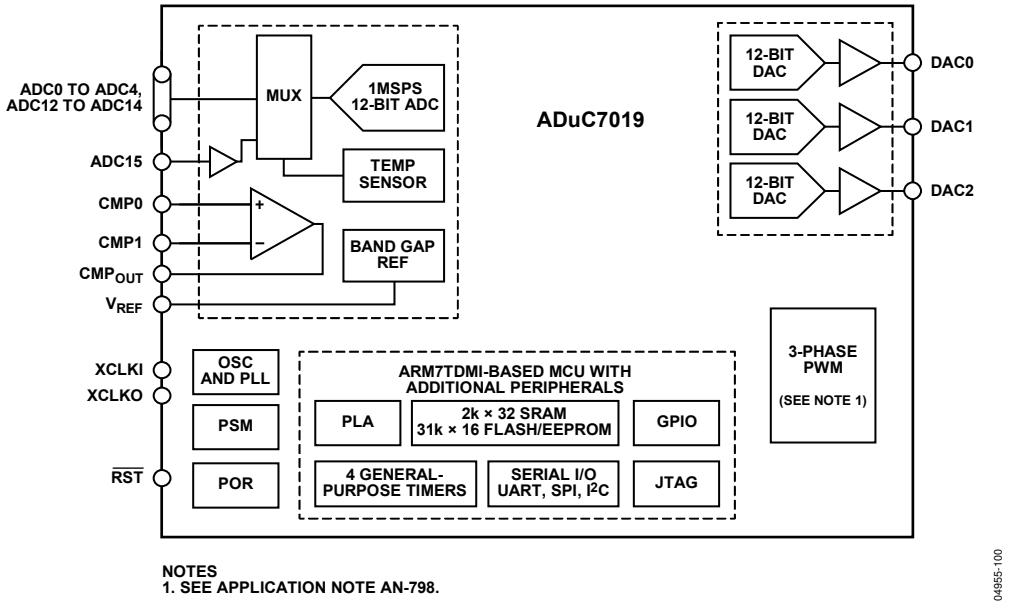

Figure 1.

[1] Depending on part model. See Ordering Guide for more information.

Rev. G Document Feedback

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REVISION HISTORY

12/15—Rev. F to Rev. G

Changed CP-40-1 to CP-40-9 ..... Universal
Updated Outline Dimensions 97
Deleted Figure 96 (CP-40-1); Renumbered Sequentially 97
Changes to Ordering Guide 101

5/13—Rev. E to Rev. F

Changes to Figure 1 1
Added Figure 2 to Figure 10; Renumbered Sequentially 4
Changes to Figure 19; Added Figure 20 21
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Updated Outline Dimensions 97
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7/12—Rev. D to Rev. E

Changed SCLOCK to SCLK When Refering to SPI Clock, SPIMISO to MISO when Refering to SPI MISO, SPIMOSI to MOSI when Refering to SPI MOSI, and SPICSL to $\overline{CS}$ when Refering to SPI Chip Select ..... Universal
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3/07—Rev. A to Rev. B

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1/06—Rev. 0 to Rev. A

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10/05—Revision 0: Initial Version

GENERAL DESCRIPTION

The ADuC7019/20/21/22/24/25/26/27/28/29 are fully integrated, 1 MSPS, 12-bit data acquisition systems incorporating high performance multichannel ADCs, 16-bit/32-bit MCUs, and Flash®/EE memory on a single chip.

The ADC consists of up to 12 single-ended inputs. An additional four inputs are available but are multiplexed with the four DAC output pins. The four DAC outputs are available only on certain models (ADuC7020, ADuC7026, ADuC7028, and ADuC7029). However, in many cases where the DAC outputs are not present, these pins can still be used as additional ADC inputs, giving a maximum of 16 ADC input channels. The ADC can operate in single-ended or differential input mode. The ADC input voltage is 0 V to V_{REF}. A low drift band gap reference, temperature sensor, and voltage comparator complete the ADC peripheral set.

Depending on the part model, up to four buffered voltage output DACs are available on-chip. The DAC output range is programmable to one of three voltage ranges.

The devices operate from an on-chip oscillator and a PLL generating an internal high frequency clock of 41.78 MHz (UCLK). This clock is routed through a programmable clock divider from which the MCU core clock operating frequency is generated. The microcontroller core is an ARM7TDMI®, 16-bit/32-bit RISC machine, which offers up to 41 MIPS peak performance. Eight kilobytes of SRAM and 62 kilobytes of nonvolatile Flash/EE memory are provided on-chip. The ARM7TDMI core views all memory and registers as a single linear array.

On-chip factory firmware supports in-circuit serial download via the UART or I²C serial interface port; nonintrusive emulation is also supported via the JTAG interface. These features are incorporated into a low cost QuickStart™ development system supporting this MicroConverter® family.

The parts operate from 2.7 V to 3.6 V and are specified over an industrial temperature range of −40°C to +125°C. When operating at 41.78 MHz, the power dissipation is typically 120 mW. The ADuC7019/20/21/22/24/25/26/27/28/29 are available in a variety of memory models and packages (see Ordering Guide).

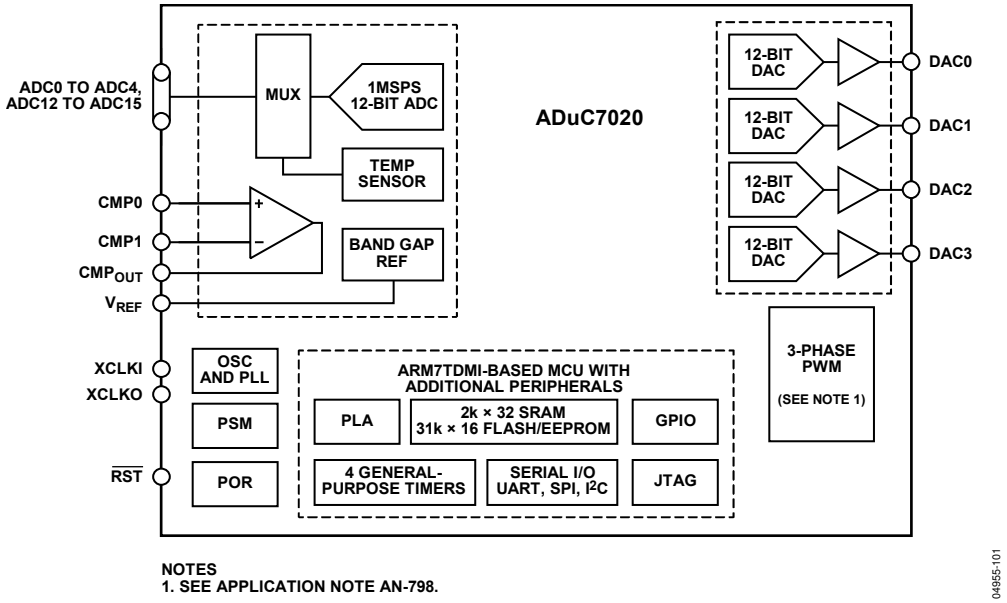


Figure 2.

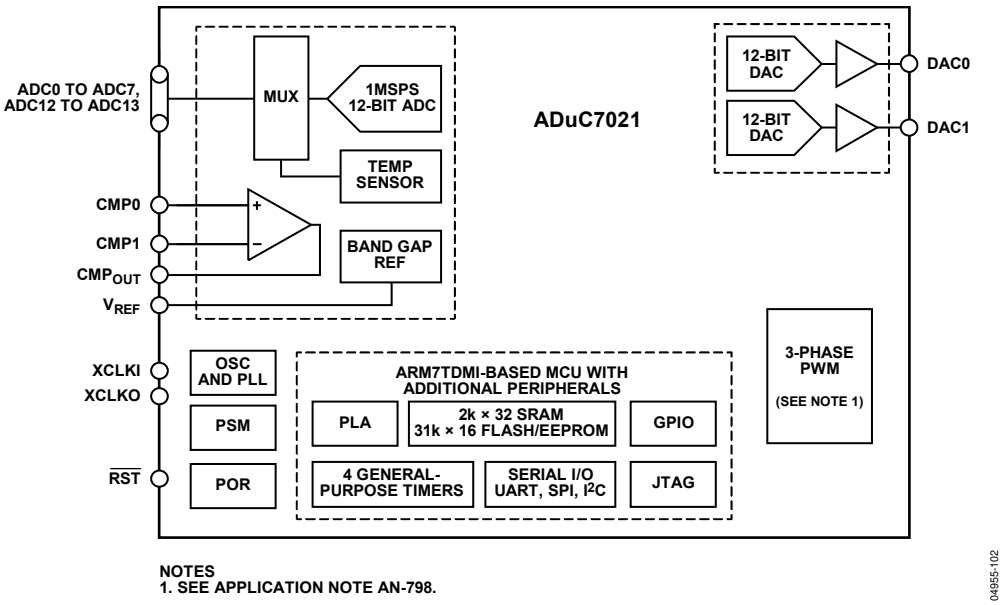


Figure 3.

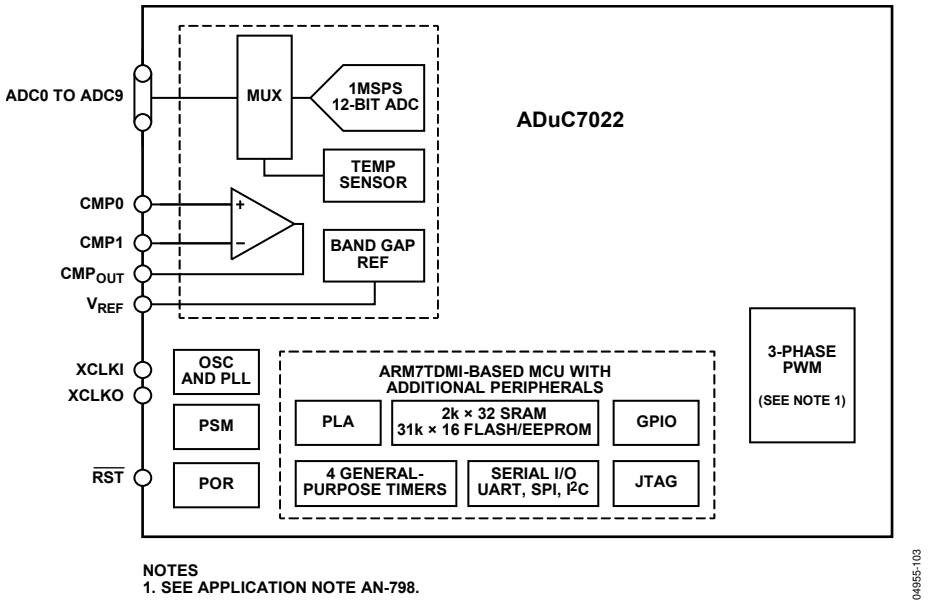


Figure 4.

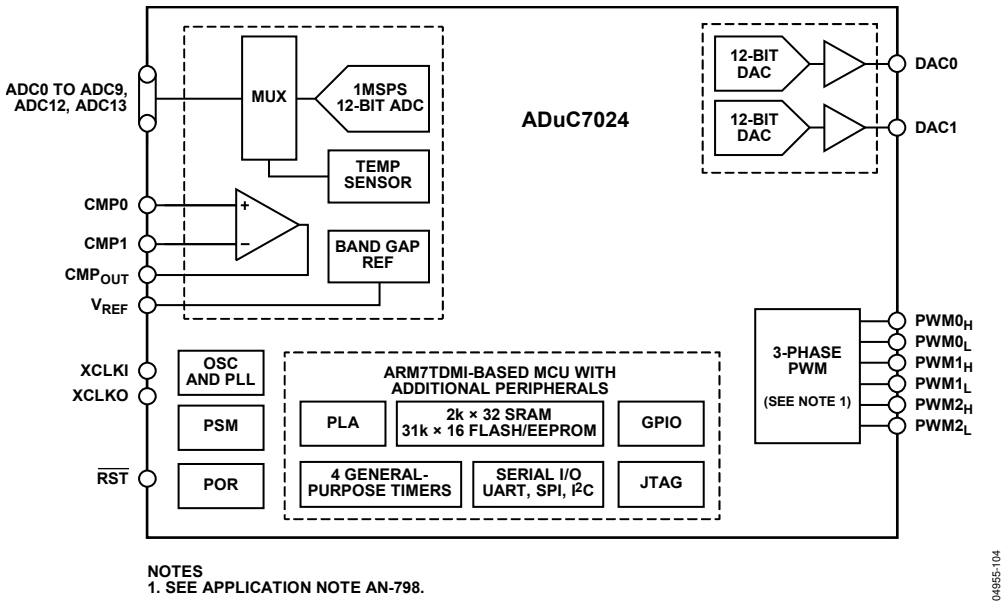


Figure 5.

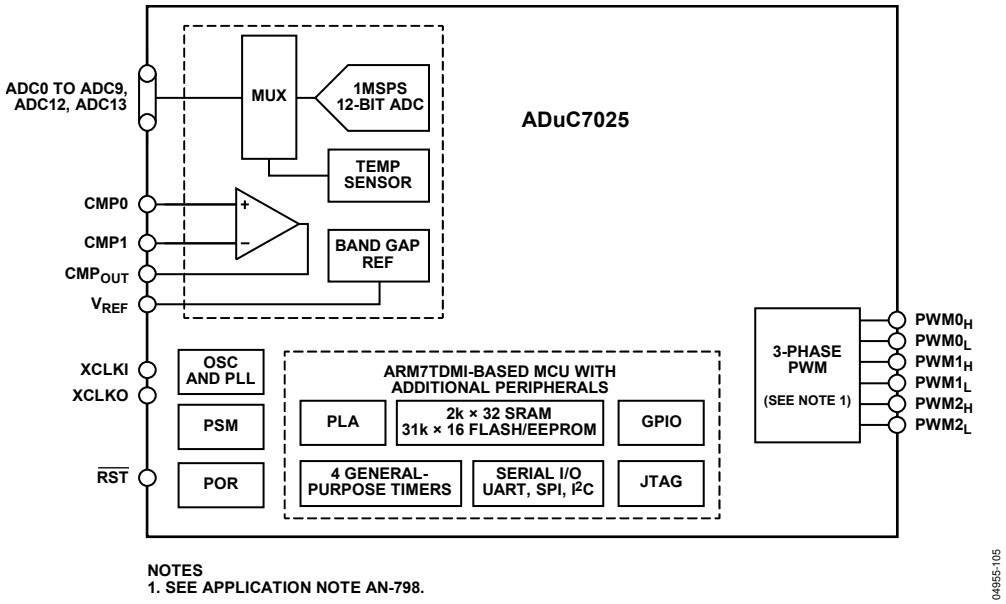


Figure 6.

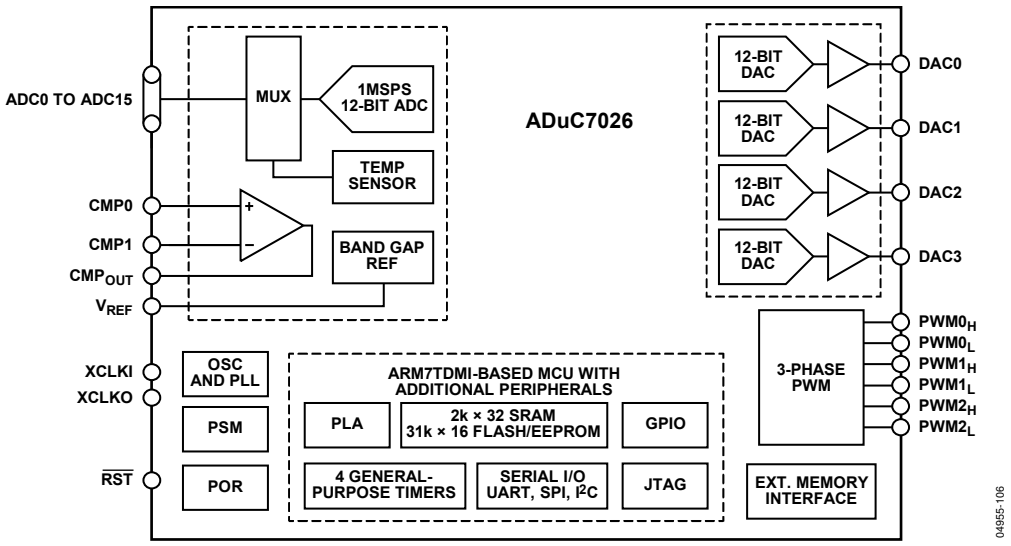


Figure 7.

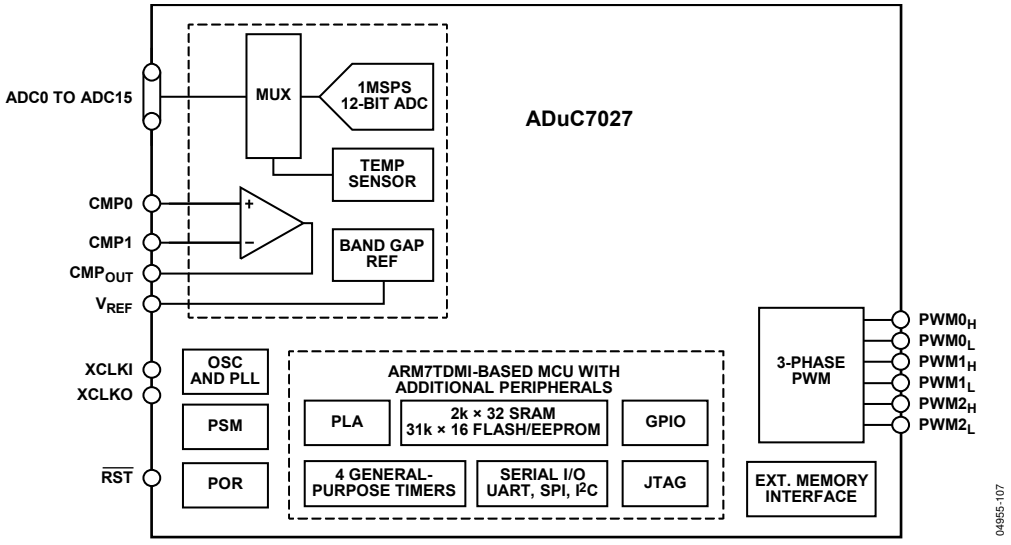


Figure 8.

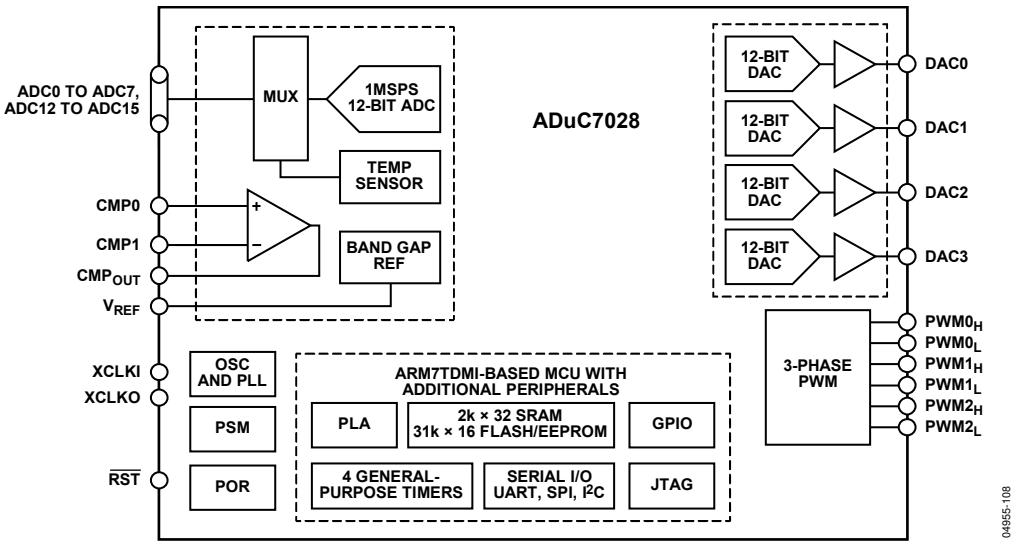


Figure 9.

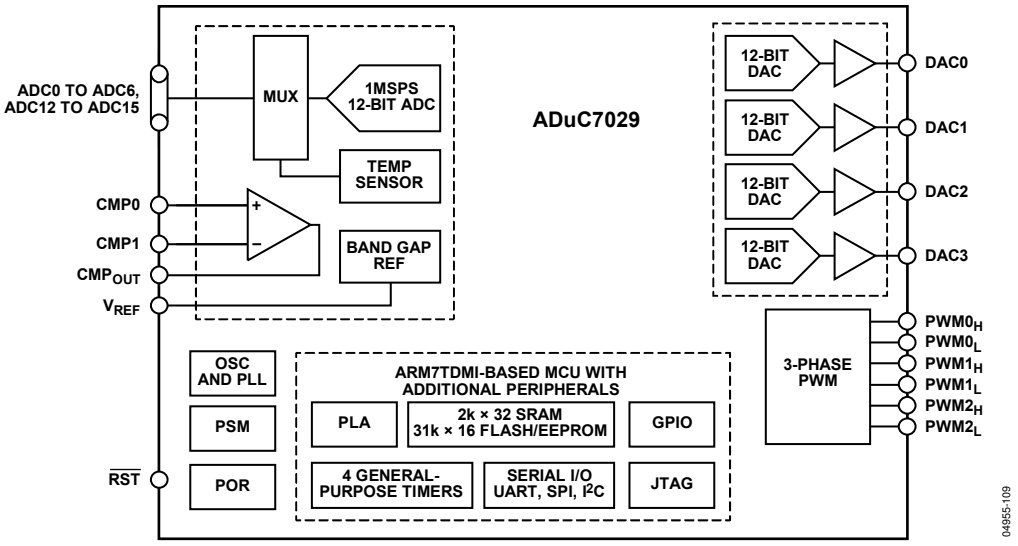


Figure 10.

DETAILED BLOCK DIAGRAM

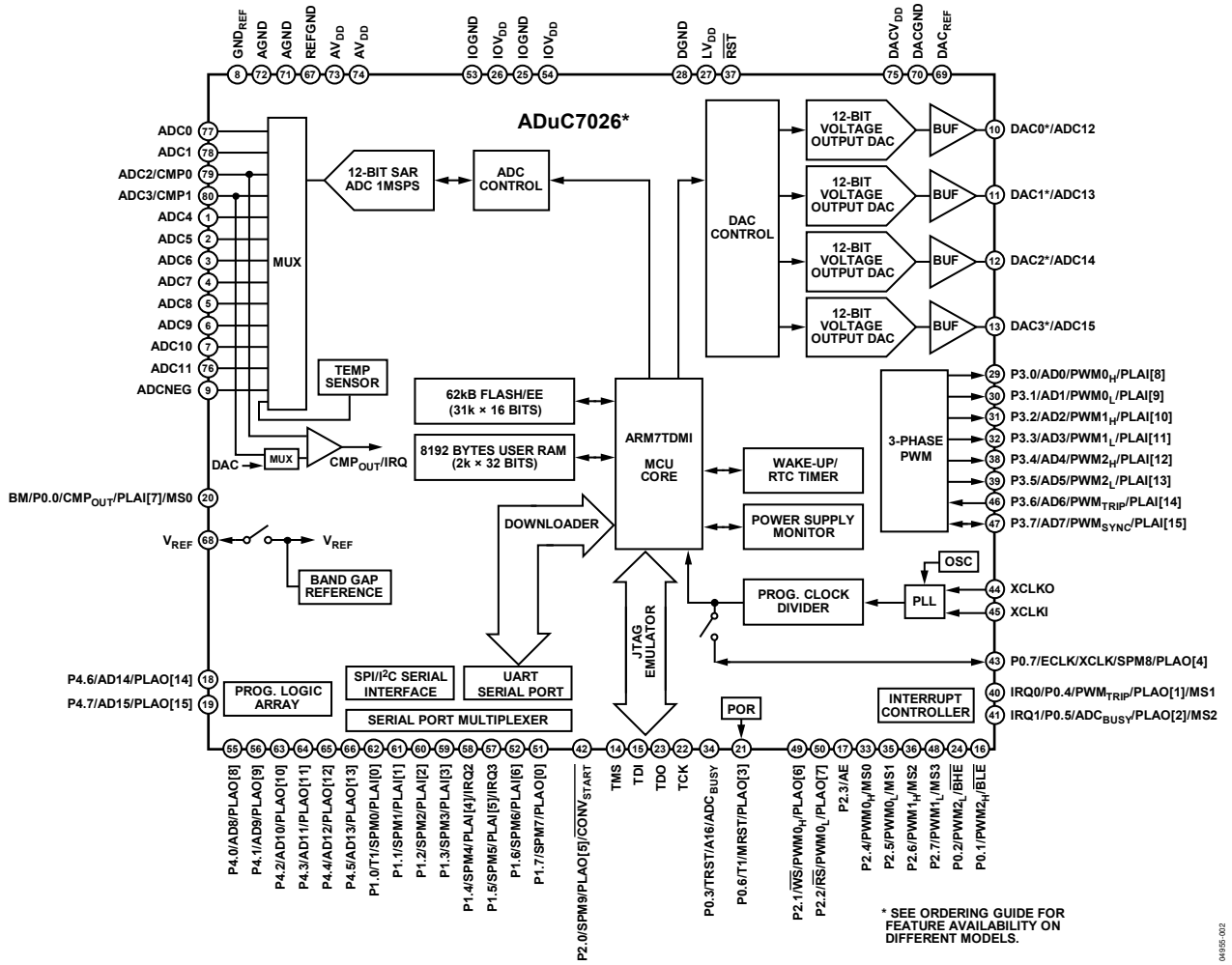


Figure 11.

SPECIFICATIONS

AV_{DD} = IOV_{DD} = 2.7 V to 3.6 V, V_{REF} = 2.5 V internal reference, f_{CORE} = 41.78 MHz, T_A = −40°C to +125°C, unless otherwise noted.

Table 1.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
ADC CHANNEL SPECIFICATIONS					Eight acquisition clocks and fADC/2
ADC Power-Up Time		5		µs	
DC Accuracy[1, 2]					
Resolution	12			Bits	
Integral Nonlinearity		±0.6	±1.5	LSB	2.5 V internal reference
		±1.0		LSB	1.0 V external reference
Differential Nonlinearity[3, 4]		±0.5	+1/−0.9	LSB	2.5 V internal reference
		+0.7/−0.6		LSB	1.0 V external reference
DC Code Distribution		1		LSB	ADC input is a dc voltage
ENDPOINT ERRORS[5]					
Offset Error		±1	±2	LSB	
Offset Error Match		±1		LSB	
Gain Error		±2	±5	LSB	
Gain Error Match		±1		LSB	
DYNAMIC PERFORMANCE					f_{IN} = 10 kHz sine wave, f_{SAMPLE} = 1 MSPS
Signal-to-Noise Ratio (SNR)		69		dB	Includes distortion and noise components
Total Harmonic Distortion (THD)		−78		dB	
Peak Harmonic or Spurious Noise (PHSN)		−75		dB	
Channel-to-Channel Crosstalk		−80		dB	Measured on adjacent channels
ANALOG INPUT					
Input Voltage Ranges					
Differential Mode			V_{CM}[6] ± V_{REF}/2	V	
Single-Ended Mode			0 to V_{REF}	V	
Leakage Current		±1	±6	µA	
Input Capacitance		20		pF	During ADC acquisition
ON-CHIP VOLTAGE REFERENCE					0.47 µF from V_{REF} to AGND
Output Voltage		2.5		V	
Accuracy			±5	mV	T_A = 25°C
Reference Temperature Coefficient		±40		ppm/°C	
Power Supply Rejection Ratio		75		dB	
Output Impedance		70		Ω	T_A = 25°C
Internal V_{REF} Power-On Time		1		ms	
EXTERNAL REFERENCE INPUT					
Input Voltage Range	0.625		AV_{DD}	V	
DAC CHANNEL SPECIFICATIONS					R_L = 5 kΩ, C_L = 100 pF
DC Accuracy[7]					
Resolution		12		Bits	
Relative Accuracy		±2		LSB	
Differential Nonlinearity			±1	LSB	Guaranteed monotonic
Offset Error			±15	mV	2.5 V internal reference
Gain Error[8]			±1	%	
Gain Error Mismatch		0.1		%	% of full scale on DAC0
ANALOG OUTPUTS					
Output Voltage Range_0		0 to DAC_{REF}		V	DAC_{REF} range: DACGND to $DACV_{DD}$
Output Voltage Range_1		0 to 2.5		V	
Output Voltage Range_2		0 to $DACV_{DD}$		V	
Output Impedance		2		Ω	

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
DAC AC CHARACTERISTICS					
Voltage Output Settling Time		10		µs	
Digital-to-Analog Glitch Energy		±20		nV-sec	1 LSB change at major carry (where maximum number of bits simultaneously changes in the DACxDAT register)
COMPARATOR					
Input Offset Voltage		±15		mV	
Input Bias Current		1		µA	
Input Voltage Range	AGND		AV_{DD} – 1.2	V	
Input Capacitance		7		pF	
Hysteresis[4, 6]	2		15	mV	Hysteresis turned on or off via the CMPHYST bit in the CMPCON register
Response Time		3		µs	100 mV overdrive and configured with CMPRES = 11
TEMPERATURE SENSOR					
Voltage Output at 25°C		780		mV	
Voltage TC		−1.3		mV/°C	
Accuracy		±3		°C	
POWER SUPPLY MONITOR (PSM)					
IOV_{DD} Trip Point Selection		2.79		V	Two selectable trip points
		3.07		V	
Power Supply Trip Point Accuracy		±2.5		%	Of the selected nominal trip point voltage
POWER-ON-RESET		2.36		V	
GLITCH IMMUNITY ON RESET PIN[4]		50		µs	
WATCHDOG TIMER (WDT)					
Timeout Period	0		512	sec	
FLASH/EE MEMORY					
Endurance[9]	10,000			Cycles	
Data Retention[10]	20			Years	T_J = 85°C
DIGITAL INPUTS					All digital inputs excluding XCLKI and XCLKO
Logic 1 Input Current		±0.2	±1	µA	V_{IH} = IOV_{DD} or V_{IH} = 5 V
Logic 0 Input Current		−40	−60	µA	V_{IL} = 0 V; except TDI on ADuC7019/20/21/22/24/25/29
		−80	−120	µA	V_{IL} = 0 V; TDI on ADuC7019/20/21/22/24/25/29
Input Capacitance		10		pF	
LOGIC INPUTS[3]					All logic inputs excluding XCLKI
V_{INL}, Input Low Voltage			0.8	V	
V_{INH}, Input High Voltage	2.0			V	
LOGIC OUTPUTS					All digital outputs excluding XCLKO
V_{OH}, Output High Voltage	2.4			V	I_{SOURCE} = 1.6 mA
V_{OL}, Output Low Voltage[11]			0.4	V	I_{SINK} = 1.6 mA
CRYSTAL INPUTS XCLKI and XCLKO					
Logic Inputs, XCLKI Only					
V_{INL}, Input Low Voltage		1.1		V	
V_{INH}, Input High Voltage		1.7		V	
XCLKI Input Capacitance		20		pF	
XCLKO Output Capacitance		20		pF	
INTERNAL OSCILLATOR		32.768		kHz	
			±3	%	
			±2[4]	%	T_A = 0°C to 85°C range

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
MCU CLOCK RATE					
From 32 kHz Internal Oscillator		326		kHz	CD[12] = 7
From 32 kHz External Crystal		41.78		MHz	CD[12] = 0
Using an External Clock	0.05		44	MHz	T_A = 85°C
	0.05		41.78	MHz	T_A = 125°C
START-UP TIME					Core clock = 41.78 MHz
At Power-On		130		ms	
From Pause/Nap Mode		24		ns	CD[12] = 0
		3.06		µs	CD[12] = 7
From Sleep Mode		1.58		ms	
From Stop Mode		1.7		ms	
PROGRAMMABLE LOGIC ARRAY (PLA)					
Pin Propagation Delay		12		ns	From input pin to output pin
Element Propagation Delay		2.5		ns	
POWER REQUIREMENTS[13, 14]					
Power Supply Voltage Range					
AV_{DD} to AGND and IOV_{DD} to IOGND	2.7		3.6	V	
Analog Power Supply Currents					
AV_{DD} Current		200		µA	ADC in idle mode; all parts except ADuC7019
		400		µA	ADC in idle mode; ADuC7019 only
$DACV_{DD}$ Current[15]		3	25	µA	
Digital Power Supply Current					
IOV_{DD} Current in Normal Mode					Code executing from Flash/EE
		7	10	mA	CD[12] = 7
		11	15	mA	CD[12] = 3
		40	45	mA	CD[12] = 0 (41.78 MHz clock)
IOV_{DD} Current in Pause Mode		25	30	mA	CD[12] = 0 (41.78 MHz clock)
IOV_{DD} Current in Sleep Mode		250	400	µA	T_A = 85°C
		600	1000	µA	T_A = 125°C
Additional Power Supply Currents					
ADC		2		mA	@ 1 MSPS
		0.7		mA	@ 62.5 kSPS
DAC		700		µA	per DAC
ESD TESTS					2.5 V reference, T_A = 25°C
HBM Passed Up To			4	kV	
FCIDM Passed Up To			0.5	kV	

[1] All ADC channel specifications are guaranteed during normal MicroConverter core operation.
[2] Apply to all ADC input channels.
[3] Measured using the factory-set default values in the ADC offset register (ADCOF) and gain coefficient register (ADCGN).
[4] Not production tested but supported by design and/or characterization data on production release.
[5] Measured using the factory-set default values in ADCOF and ADCGN with an external AD845 op amp as an input buffer stage as shown in Figure 59. Based on external ADC system components; the user may need to execute a system calibration to remove external endpoint errors and achieve these specifications (see the Calibration section).
[6] The input signal can be centered on any dc common-mode voltage (V_{CM}) as long as this value is within the ADC voltage input range specified.
[7] DAC linearity is calculated using a reduced code range of 100 to 3995.
[8] DAC gain error is calculated using a reduced code range of 100 to internal 2.5 V V_{REF}.
[9] Endurance is qualified as per JEDEC Standard 22, Method A117 and measured at −40°C, +25°C, +85°C, and +125°C.
[10] Retention lifetime equivalent at junction temperature (T_J) = 85°C as per JEDEC Standard 22m, Method A117. Retention lifetime derates with junction temperature.
[11] Test carried out with a maximum of eight I/Os set to a low output level.
[12] See the POWCON register.
[13] Power supply current consumption is measured in normal, pause, and sleep modes under the following conditions: normal mode with 3.6 V supply, pause mode with 3.6 V supply, and sleep mode with 3.6 V supply.
[14] IOV_{DD} power supply current decreases typically by 2 mA during a Flash/EE erase cycle.
[15] On the ADuC7019/20/21/22, this current must be added to the AV_{DD} current.

TIMING SPECIFICATIONS

Table 2. External Memory Write Cycle

Parameter	Min	Typ	Max	Unit
CLK[1]		UCLK		
$t_{MS\_AFTER\_CLKH}$	0		4	ns
$t_{ADDR\_AFTER\_CLKH}$	4		8	ns
$t_{AE\_H\_AFTER\_MS}$		½ CLK		
t_{AE}		(XMxPAR[14:12] + 1) × CLK		
$t_{HOLD\_ADDR\_AFTER\_AE\_L}$		½ CLK + (!XMxPAR[10]) × CLK		
$t_{HOLD\_ADDR\_BEFORE\_WR\_L}$		(!XMxPAR[8]) × CLK		
$t_{WR\_L\_AFTER\_AE\_L}$		½ CLK + (!XMxPAR[10] + !XMxPAR[8]) × CLK		
$t_{DATA\_AFTER\_WR\_L}$	8		12	ns
t_{WR}		(XMxPAR[7:4] + 1) × CLK		
$t_{WR\_H\_AFTER\_CLKH}$	0		4	ns
$t_{HOLD\_DATA\_AFTER\_WR\_H}$		(!XMxPAR[8]) × CLK		
$t_{BEN\_AFTER\_AE\_L}$		½ CLK		
$t_{RELEASE\_MS\_AFTER\_WR\_H}$		(!XMxPAR[8] + 1) × CLK		

[1] See Table 78.

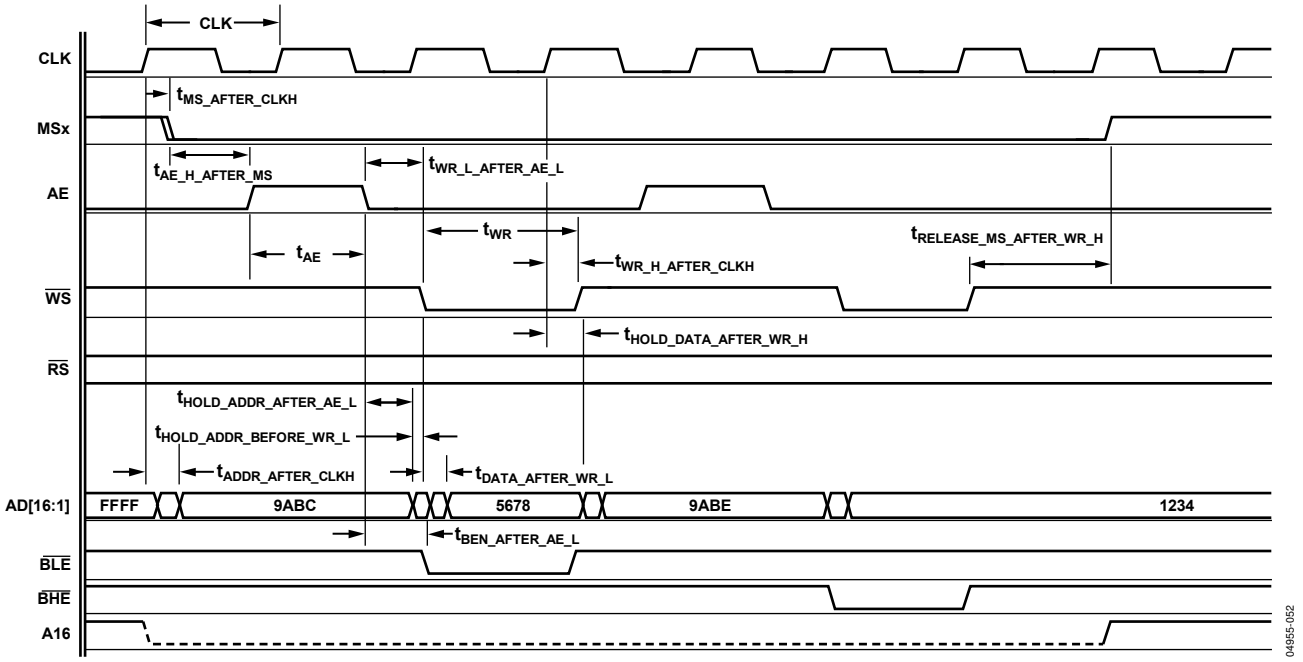


Figure 12. External Memory Write Cycle (See Table 78)

Table 3. External Memory Read Cycle

Parameter	Min	Typ	Max	Unit
CLK[1]	1/MD clock	ns typ × (POWCON[2:0] + 1)		
$t_{MS\_AFTER\_CLKH}$	4		8	ns
$t_{ADDR\_AFTER\_CLKH}$	4		16	ns
$t_{AE\_H\_AFTER\_MS}$		½ CLK		
t_{AE}		(XMxPAR[14:12] + 1) × CLK		
$t_{HOLD\_ADDR\_AFTER\_AE\_L}$		½ CLK + (! XMxPAR[10]) × CLK		
$t_{RD\_L\_AFTER\_AE\_L}$		½ CLK + (! XMxPAR[10]+ ! XMxPAR[9]) × CLK		
$t_{RD\_H\_AFTER\_CLKH}$	0		4	
t_{RD}		(XMxPAR[3:0] + 1) × CLK		
$t_{DATA\_BEFORE\_RD\_H}$	16			ns
$t_{DATA\_AFTER\_RD\_H}$	8	+ (! XMxPAR[9]) × CLK		
$t_{RELEASE\_MS\_AFTER\_RD\_H}$		1 × CLK		

[1] See Table 78.

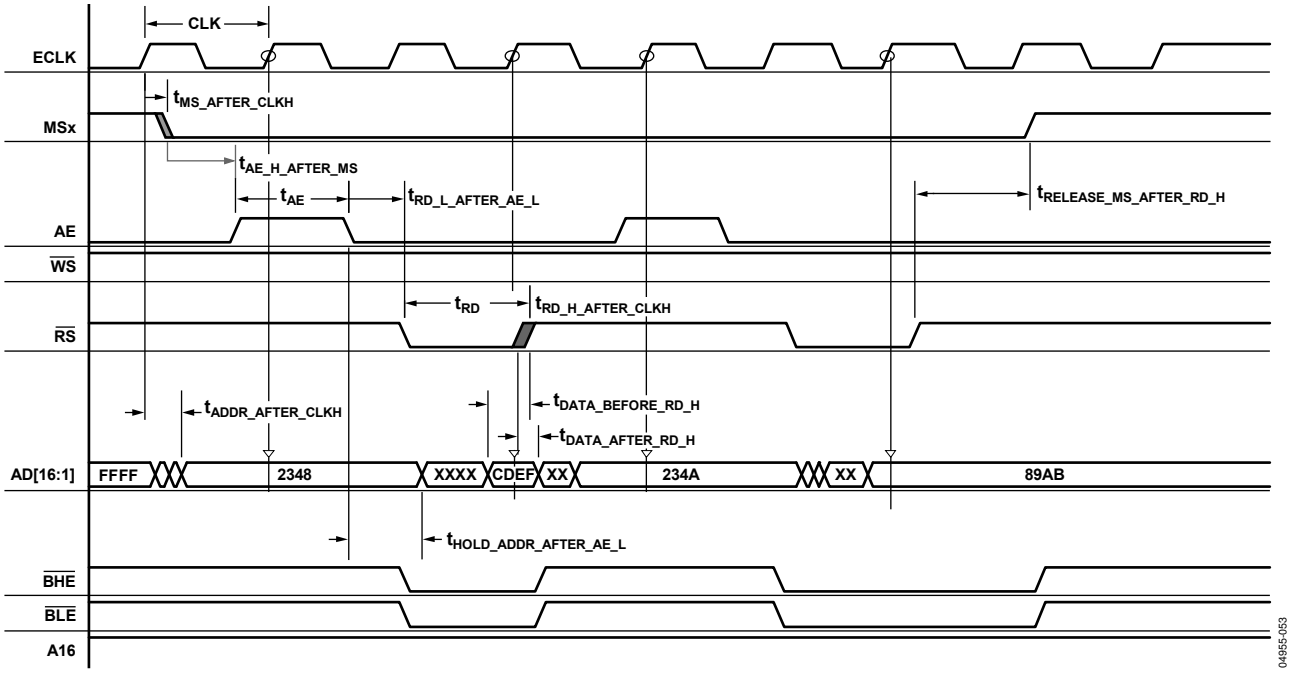


Figure 13. External Memory Read Cycle (See Table 78)

Table 4. I²C Timing in Fast Mode (400 kHz)

		Slave		Master	
Parameter	**Description**	**Min**	**Max**	**Typ**	**Unit**
t_L	SCL low pulse width[1]	200		1360	ns
t_H	SCL high pulse width[1]	100		1140	ns
t_{SHD}	Start condition hold time	300			ns
t_{DSU}	Data setup time	100		740	ns
t_{DHD}	Data hold time	0		400	ns
t_{RSU}	Setup time for repeated start	100			ns
t_{PSU}	Stop condition setup time	100		400	ns
t_{BUF}	Bus-free time between a stop condition and a start condition	1.3			µs
t_R	Rise time for both SCL and SDA		300	200	ns
t_F	Fall time for both SCL and SDA		300		ns
t_{SUP}	Pulse width of spike suppressed		50		ns

[1] t_{HCLK} depends on the clock divider or CD bits in the POWCON MMR. $t_{HCLK} = t_{UCLK}/2^{CD}$; see Figure 67.

Table 5. I²C Timing in Standard Mode (100 kHz)

		Slave		Master	
Parameter	**Description**	**Min**	**Max**	**Typ**	**Unit**
t_L	SCL low pulse width[1]	4.7			µs
t_H	SCL high pulse width[1]	4.0			ns
t_{SHD}	Start condition hold time	4.0			µs
t_{DSU}	Data setup time	250			ns
t_{DHD}	Data hold time	0	3.45		µs
t_{RSU}	Setup time for repeated start	4.7			µs
t_{PSU}	Stop condition setup time	4.0			µs
t_{BUF}	Bus-free time between a stop condition and a start condition	4.7			µs
t_R	Rise time for both SCL and SDA		1		µs
t_F	Fall time for both SCL and SDA		300		ns

[1] t_{HCLK} depends on the clock divider or CD bits in the POWCON MMR. $t_{HCLK} = t_{UCLK}/2^{CD}$; see Figure 67.

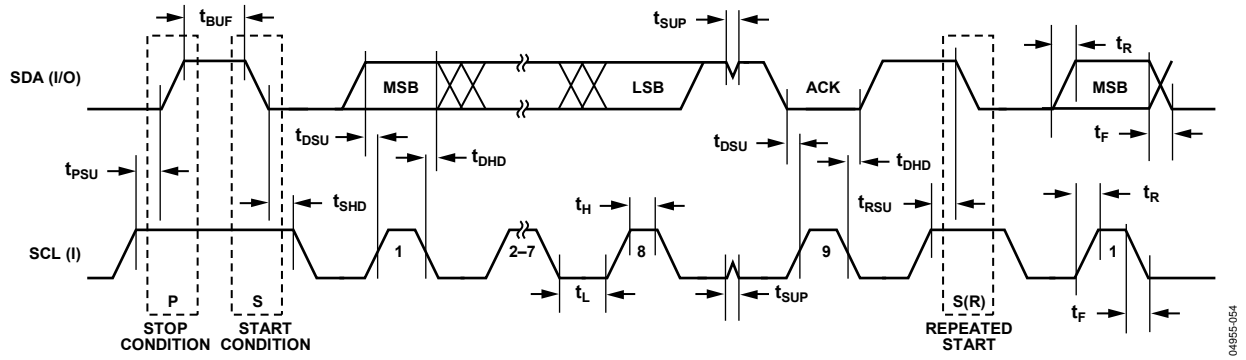


Figure 14. I²C Compatible Interface Timing

Table 6. SPI Master Mode Timing (Phase Mode = 1)

Parameter	Description	Min	Typ	Max	Unit
t_{SL}	SCLK low pulse width[1]		(SPIDIV + 1) × t_{HCLK}		ns
t_{SH}	SCLK high pulse width[1]		(SPIDIV + 1) × t_{HCLK}		ns
t_{DAV}	Data output valid after SCLK edge			25	ns
t_{DSU}	Data input setup time before SCLK edge[2]	1 × t_{UCLK}			ns
t_{DHD}	Data input hold time after SCLK edge[2]	2 × t_{UCLK}			ns
t_{DF}	Data output fall time		5	12.5	ns
t_{DR}	Data output rise time		5	12.5	ns
t_{SR}	SCLK rise time		5	12.5	ns
t_{SF}	SCLK fall time		5	12.5	ns

[1] t_{HCLK} depends on the clock divider or CD bits in the POWCONMMR. $t_{HCLK} = t_{UCLK}/2^{CD}$; see Figure 67.
[2] t_{UCLK} = 23.9 ns. It corresponds to the 41.78 MHz internal clock from the PLL before the clock divider; see Figure 67.

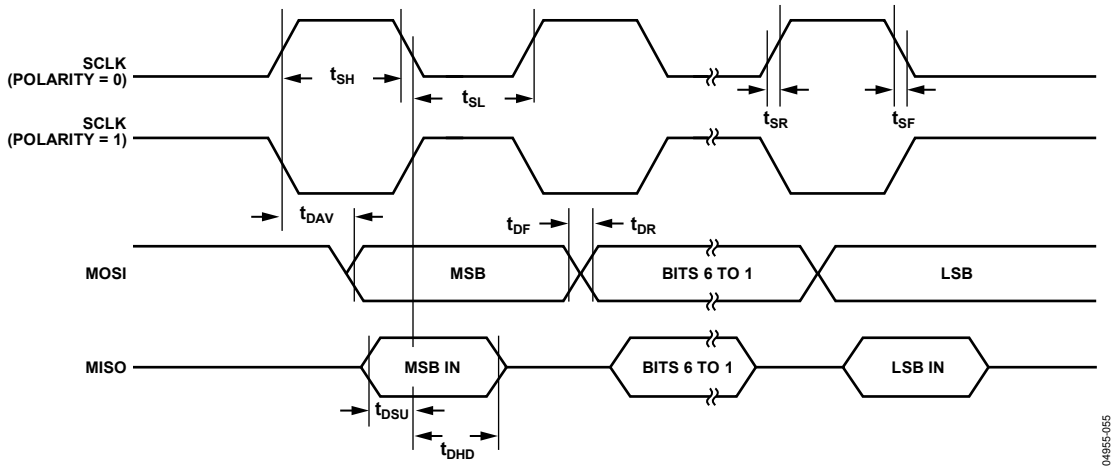


Figure 15. SPI Master Mode Timing (Phase Mode = 1)

Table 7. SPI Master Mode Timing (Phase Mode = 0)

Parameter	Description	Min	Typ	Max	Unit
t_{SL}	SCLK low pulse width[1]		(SPIDIV + 1) × t_{HCLK}		ns
t_{SH}	SCLK high pulse width[1]		(SPIDIV + 1) × t_{HCLK}		ns
t_{DAV}	Data output valid after SCLK edge			25	ns
t_{DOSU}	Data output setup before SCLK edge			75	ns
t_{DSU}	Data input setup time before SCLK edge[2]	1 × t_{UCLK}			ns
t_{DHD}	Data input hold time after SCLK edge[2]	2 × t_{UCLK}			ns
t_{DF}	Data output fall time		5	12.5	ns
t_{DR}	Data output rise time		5	12.5	ns
t_{SR}	SCLK rise time		5	12.5	ns
t_{SF}	SCLK fall time		5	12.5	ns

[1] t_{HCLK} depends on the clock divider or CD bits in the POWCONMMR. $t_{HCLK} = t_{UCLK}/2^{CD}$; see Figure 67.
[2] t_{UCLK} = 23.9 ns. It corresponds to the 41.78 MHz internal clock from the PLL before the clock divider; see Figure 67.

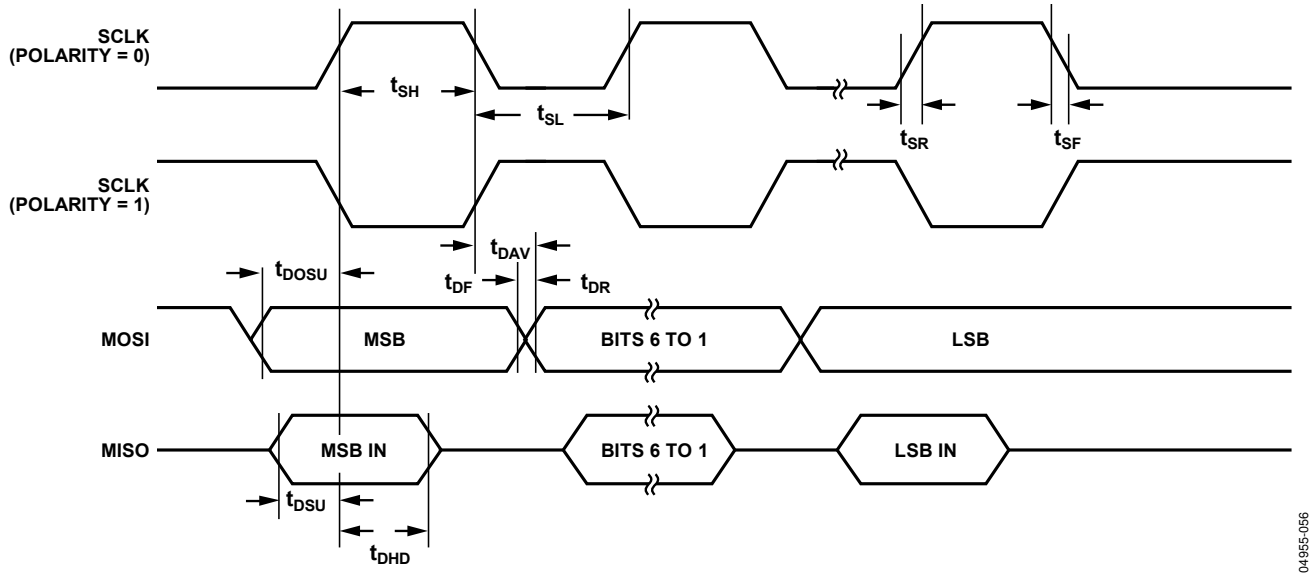


Figure 16. SPI Master Mode Timing (Phase Mode = 0)

Table 8. SPI Slave Mode Timing (Phsae Mode = 1)

Parameter	Description	Min	Typ	Max	Unit
$t_{\overline{CS}}$	$\overline{CS}$ to SCLK edge[1]	$(2 \times t_{HCLK}) + (2 \times t_{UCLK})$			ns
t_{SL}	SCLK low pulse width[2]		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{SH}	SCLK high pulse width[2]		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{DAV}	Data output valid after SCLK edge			25	ns
t_{DSU}	Data input setup time before SCLK edge[1]	$1 \times t_{UCLK}$			ns
t_{DHD}	Data input hold time after SCLK edge[1]	$2 \times t_{UCLK}$			ns
t_{DF}	Data output fall time		5	12.5	ns
t_{DR}	Data output rise time		5	12.5	ns
t_{SR}	SCLK rise time		5	12.5	ns
t_{SF}	SCLK fall time		5	12.5	ns
t_{SFS}	$\overline{CS}$ high after SCLK edge	0			ns

[1] t_{UCLK} = 23.9 ns. It corresponds to the 41.78 MHz internal clock from the PLL before the clock divider; see Figure 67.
[2] t_{HCLK} depends on the clock divider or CD bits in the POWCONMMR. $t_{HCLK} = t_{UCLK}/2^{CD}$; see Figure 67.

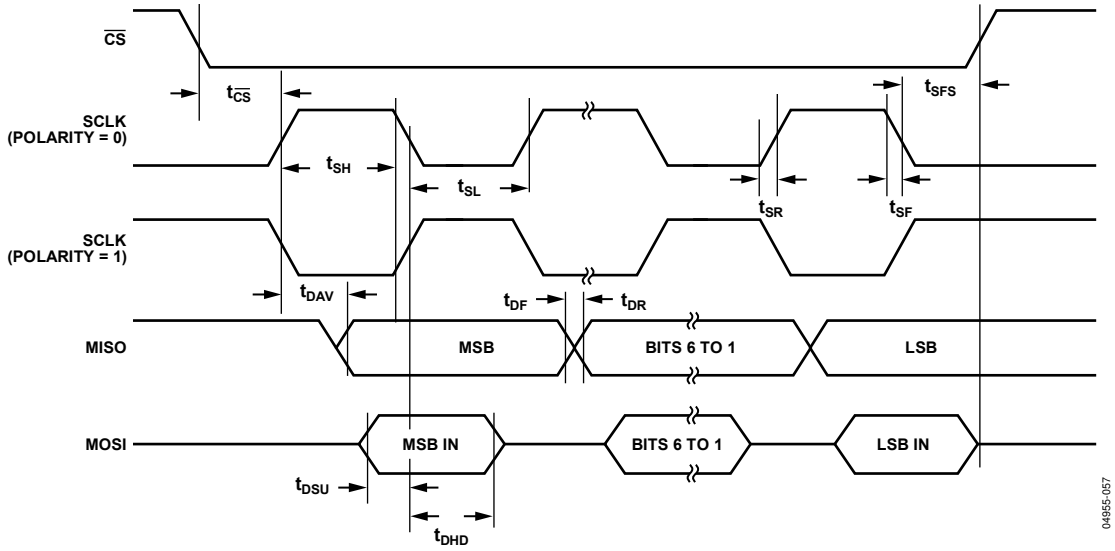


Figure 17. SPI Slave Mode Timing (Phase Mode = 1)

Table 9. SPI Slave Mode Timing (Phase Mode = 0)

Parameter	Description	Min	Typ	Max	Unit
$t_{\overline{CS}}$	$\overline{CS}$ to SCLK edge[1]	$(2 \times t_{HCLK}) + (2 \times t_{UCLK})$			ns
t_{SL}	SCLK low pulse width[2]		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{SH}	SCLK high pulse width[2]		$(SPIDIV + 1) \times t_{HCLK}$		ns
t_{DAV}	Data output valid after SCLK edge			25	ns
t_{DSU}	Data input setup time before SCLK edge[1]	$1 \times t_{UCLK}$			ns
t_{DHD}	Data input hold time after SCLK edge[1]	$2 \times t_{UCLK}$			ns
t_{DF}	Data output fall time		5	12.5	ns
t_{DR}	Data output rise time		5	12.5	ns
t_{SR}	SCLK rise time		5	12.5	ns
t_{SF}	SCLK fall time		5	12.5	ns
t_{DOCS}	Data output valid after $\overline{CS}$ edge			25	ns
t_{SFS}	$\overline{CS}$ high after SCLK edge	0			ns

[1] t_{UCLK} = 23.9 ns. It corresponds to the 41.78 MHz internal clock from the PLL before the clock divider; see Figure 67.
[2] t_{HCLK} depends on the clock divider or CD bits in the POWCONMMR. $t_{HCLK} = t_{UCLK}/2^{CD}$; see Figure 67.

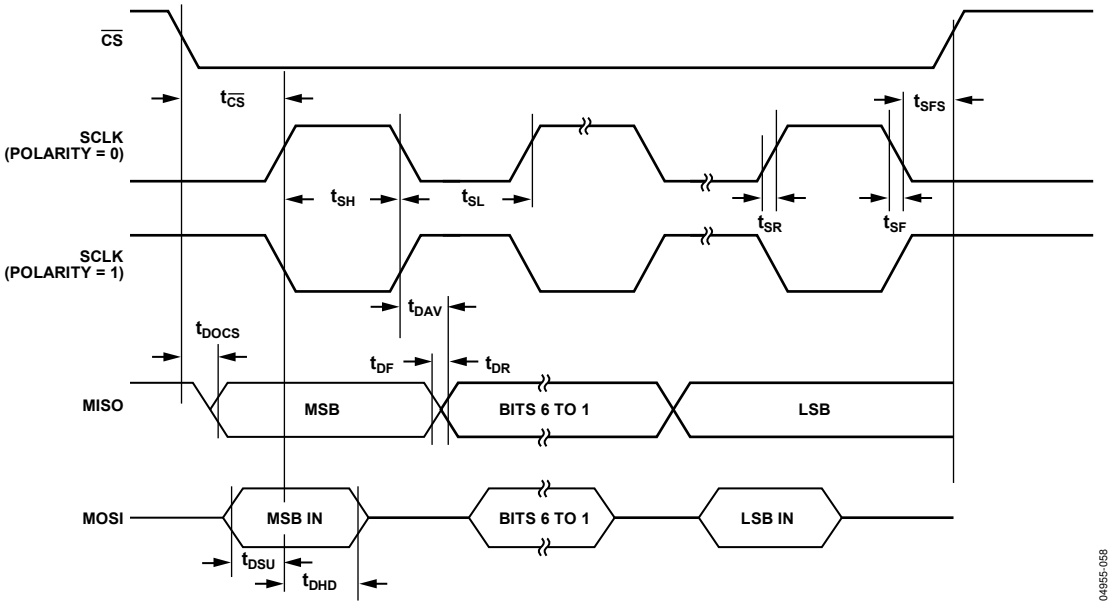


Figure 18. SPI Slave Mode Timing (Phase Mode = 0)

ABSOLUTE MAXIMUM RATINGS

AGND = REFGND = DACGND = GND_{REF}, T_A = 25°C, unless otherwise noted.

Table 10.

Parameter	Rating
AV_{DD} to IOV_{DD}	−0.3 V to +0.3 V
AGND to DGND	−0.3 V to +0.3 V
IOV_{DD} to IOGND, AV_{DD} to AGND	−0.3 V to +6 V
Digital Input Voltage to IOGND	−0.3 V to +5.3 V
Digital Output Voltage to IOGND	−0.3 V to IOV_{DD} + 0.3 V
V_{REF} to AGND	−0.3 V to AV_{DD} + 0.3 V
Analog Inputs to AGND	−0.3 V to AV_{DD} + 0.3 V
Analog Outputs to AGND	−0.3 V to AV_{DD} + 0.3 V
Operating Temperature Range, Industrial	–40°C to +125°C
Storage Temperature Range	–65°C to +150°C
Junction Temperature	150°C
θ_{JA} Thermal Impedance	
40-Lead LFCSP	26°C/W
49-Ball CSP_BGA	80°C/W
64-Lead LFCSP	24°C/W
64-Ball CSP_BGA	75°C/W
64-Lead LQFP	47°C/W
80-Lead LQFP	38°C/W
Peak Solder Reflow Temperature	
SnPb Assemblies (10 sec to 30 sec)	240°C
RoHS Compliant Assemblies (20 sec to 40 sec)	260°C

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

Only one absolute maximum rating can be applied at any one time.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

ADuC7019/ADuC7020/ADuC7021/ADuC7022

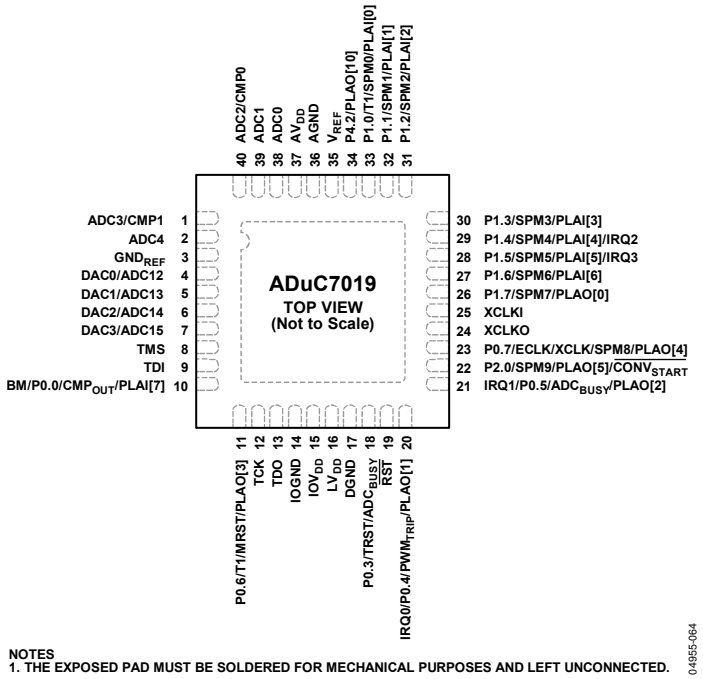


Figure 19. 40-Lead LFCSP_WQ Pin Configuration (ADuC7019)

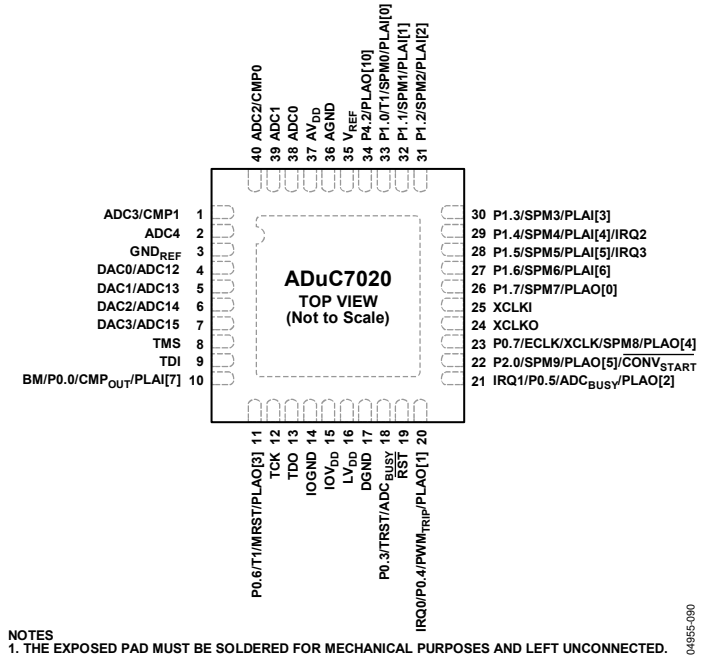
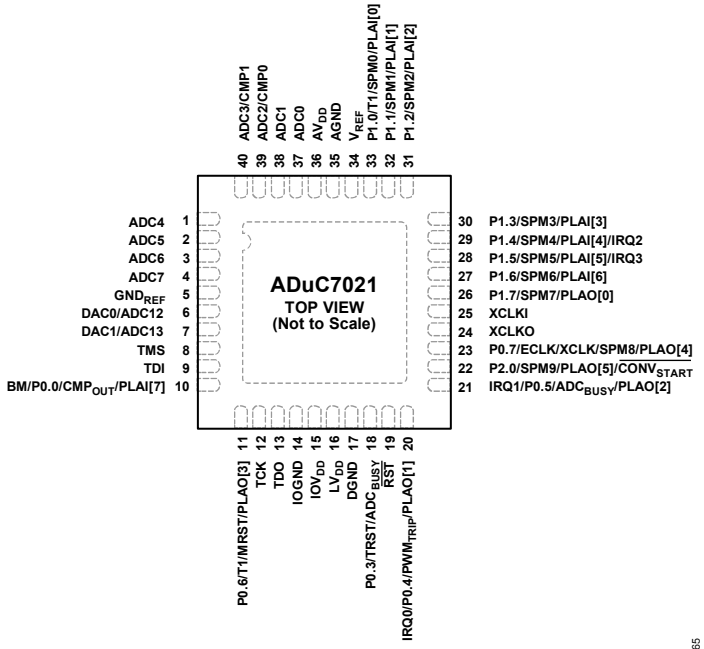


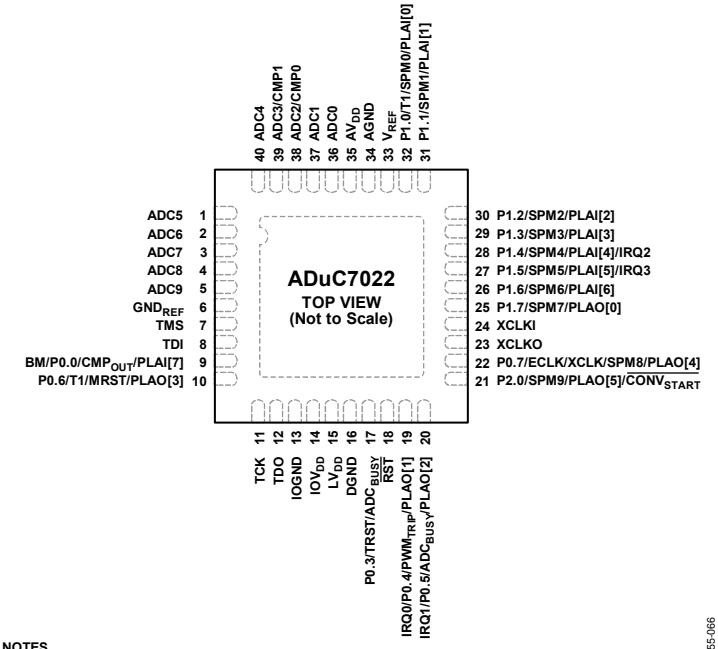
Figure 20. 40-Lead LFCSP_WQ Pin Configuration (ADuC7020)



NOTES
1. THE EXPOSED PAD MUST BE SOLDERED FOR MECHANICAL PURPOSES AND LEFT UNCONNECTED.

04955-065

Figure 21. 40-Lead LFCSP_WQ Pin Configuration (ADuC7021)



NOTES
1. THE EXPOSED PAD MUST BE SOLDERED FOR MECHANICAL PURPOSES AND LEFT UNCONNECTED.

04955-066

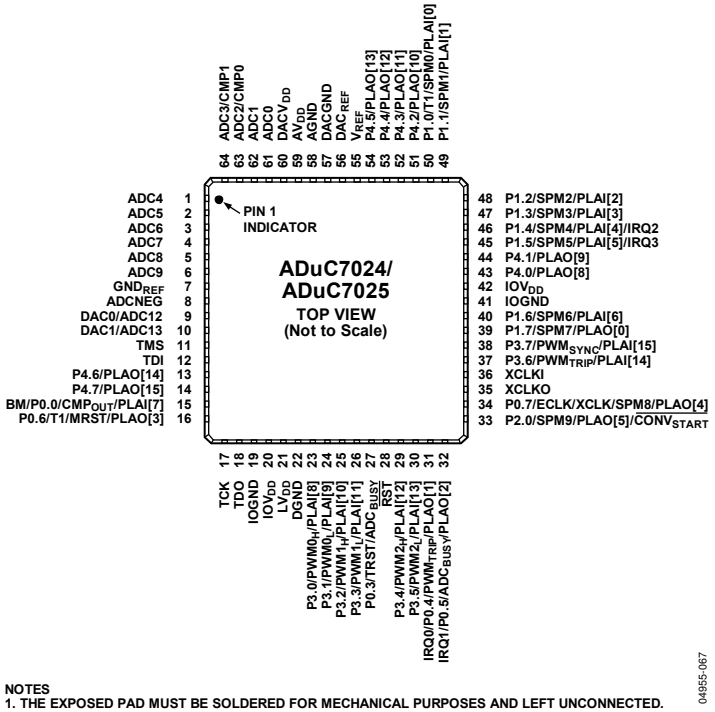
Figure 22. 40-Lead LFCSP_WQ Pin Configuration (ADuC7022)

Table 11. Pin Function Descriptions (ADuC7019/ADuC7020/ADuC7021/ADuC7022)

Pin No.				
7019/7020	7021	7022	Mnemonic	Description
38	37	36	ADC0	Single-Ended or Differential Analog Input 0.
39	38	37	ADC1	Single-Ended or Differential Analog Input 1.
40	39	38	ADC2/CMP0	Single-Ended or Differential Analog Input 2/Comparator Positive Input.
1	40	39	ADC3/CMP1	Single-Ended or Differential Analog Input 3 (Buffered Input on ADuC7019)/ Comparator Negative Input.
2	1	40	ADC4	Single-Ended or Differential Analog Input 4.
–	2	1	ADC5	Single-Ended or Differential Analog Input 5.
–	3	2	ADC6	Single-Ended or Differential Analog Input 6.
–	4	3	ADC7	Single-Ended or Differential Analog Input 7.
–	–	4	ADC8	Single-Ended or Differential Analog Input 8.
–	–	5	ADC9	Single-Ended or Differential Analog Input 9.
3	5	6	GND_{REF}	Ground Voltage Reference for the ADC. For optimal performance, the analog power supply should be separated from IOGND and DGND.
4	6	–	DAC0/ADC12	DAC0 Voltage Output/Single-Ended or Differential Analog Input 12.
5	7	–	DAC1/ADC13	DAC1 Voltage Output/Single-Ended or Differential Analog Input 13.
6	–	–	DAC2/ADC14	DAC2 Voltage Output/Single-Ended or Differential Analog Input 14.
7	–	–	DAC3/ADC15	DAC3 Voltage Output on ADuC7020. On the ADuC7019, a 10 nF capacitor must be connected between this pin and AGND/Single-Ended or Differential Analog Input 15 (see Figure 53).
8	8	7	TMS	Test Mode Select, JTAG Test Port Input. Debug and download access. This pin has an internal pull-up resistor to IOV_{DD}. In some cases, an external pull-up resistor (~100K) is also required to ensure that the part does not enter an erroneous state.
9	9	8	TDI	Test Data In, JTAG Test Port Input. Debug and download access.
10	10	9	BM/P0.0/CMP_{OUT}/PLAI[7]	Multifunction I/O Pin. Boot Mode (BM). The ADuC7019/20/21/22 enter serial download mode if BM is low at reset and execute code if BM is pulled high at reset through a 1 kΩ resistor/General-Purpose Input and Output Port 0.0/Voltage Comparator Output/Programmable Logic Array Input Element 7.
11	11	10	P0.6/T1/MRST/PLAO[3]	Multifunction Pin. Driven low after reset. General-Purpose Output Port 0.6/ Timer1 Input/Power-On Reset Output/Programmable Logic Array Output Element 3.
12	12	11	TCK	Test Clock, JTAG Test Port Input. Debug and download access. This pin has an internal pull-up resistor to IOV_{DD}. In some cases an external pull-up resistor (~100K) is also required to ensure that the part does not enter an erroneous state.
13	13	12	TDO	Test Data Out, JTAG Test Port Output. Debug and download access.
14	14	13	IOGND	Ground for GPIO (see Table 78). Typically connected to DGND.
15	15	14	IOV_{DD}	3.3 V Supply for GPIO (see Table 78) and Input of the On-Chip Voltage Regulator.
16	16	15	LV_{DD}	2.6 V Output of the On-Chip Voltage Regulator. This output must be connected to a 0.47 µF capacitor to DGND only.
17	17	16	DGND	Ground for Core Logic.
18	18	17	P0.3/TRST/ADC_{BUSY}	General-Purpose Input and Output Port 0.3/Test Reset, JTAG Test Port Input/ ADC_{BUSY} Signal Output.
19	19	18	$\overline{RST}$	Reset Input, Active Low.
20	20	19	IRQ0/P0.4/PWM_{TRIP}/PLAO[1]	Multifunction I/O Pin. External Interrupt Request 0, Active High/General-Purpose Input and Output Port 0.4/PWM Trip External Input/Programmable Logic Array Output Element 1.
21	21	20	IRQ1/P0.5/ADC_{BUSY}/PLAO[2]	Multifunction I/O Pin. External Interrupt Request 1, Active High/General-Purpose Input and Output Port 0.5/ADC_{BUSY} Signal Output/Programmable Logic Array Output Element 2.

Pin No.				
7019/7020	7021	7022	Mnemonic	Description
22	22	21	P2.0/SPM9/PLAO[5]/$\overline{CONV_{START}}$	Serial Port Multiplexed. General-Purpose Input and Output Port 2.0/UART/ Programmable Logic Array Output Element 5/Start Conversion Input Signal for ADC.
23	23	22	P0.7/ECLK/XCLK/SPM8/PLAO[4]	Serial Port Multiplexed. General-Purpose Input and Output Port 0.7/ Output for External Clock Signal/Input to the Internal Clock Generator Circuits/UART/ Programmable Logic Array Output Element 4.
24	24	23	XCLKO	Output from the Crystal Oscillator Inverter.
25	25	24	XCLKI	Input to the Crystal Oscillator Inverter and Input to the Internal Clock Generator Circuits.
26	26	25	P1.7/SPM7/PLAO[0]	Serial Port Multiplexed. General-Purpose Input and Output Port 1.7/UART, SPI/Programmable Logic Array Output Element 0.
27	27	26	P1.6/SPM6/PLAI[6]	Serial Port Multiplexed. General-Purpose Input and Output Port 1.6/UART, SPI/Programmable Logic Array Input Element 6.
28	28	27	P1.5/SPM5/PLAI[5]/IRQ3	Serial Port Multiplexed. General-Purpose Input and Output Port 1.5/UART, SPI/Programmable Logic Array Input Element 5/External Interrupt Request 3, Active High.
29	29	28	P1.4/SPM4/PLAI[4]/IRQ2	Serial Port Multiplexed. General-Purpose Input and Output Port 1.4/UART, SPI/Programmable Logic Array Input Element 4/External Interrupt Request 2, Active High.
30	30	29	P1.3/SPM3/PLAI[3]	Serial Port Multiplexed. General-Purpose Input and Output Port 1.3/UART, I2C1/Programmable Logic Array Input Element 3.
31	31	30	P1.2/SPM2/PLAI[2]	Serial Port Multiplexed. General-Purpose Input and Output Port 1.2/UART, I2C1/Programmable Logic Array Input Element 2.
32	32	31	P1.1/SPM1/PLAI[1]	Serial Port Multiplexed. General-Purpose Input and Output Port 1.1/UART, I2C0/Programmable Logic Array Input Element 1.
33	33	32	P1.0/T1/SPM0/PLAI[0]	Serial Port Multiplexed. General-Purpose Input and Output Port 1.0/ Timer1 Input/UART, I2C0/Programmable Logic Array Input Element 0.
34	–	–	P4.2/PLAO[10]	General-Purpose Input and Output Port 4.2/Programmable Logic Array Output Element 10.
35	34	33	V_{REF}	2.5 V Internal Voltage Reference. Must be connected to a 0.47 µF capacitor when using the internal reference.
36	35	34	AGND	Analog Ground. Ground reference point for the analog circuitry.
37	36	35	AV_{DD}	3.3 V Analog Power.
0	0	0	EP	Exposed Pad. The pin configuration for the ADuC7019/ADuC7020/ ADuC7021/ADuC7022 has an exposed pad that must be soldered for mechanical purposes and left unconnected.

ADuC7024/ADuC7025



NOTES
1. THE EXPOSED PAD MUST BE SOLDERED FOR MECHANICAL PURPOSES AND LEFT UNCONNECTED.

Figure 23. 64-Lead LFCSP_VQ Pin Configuration (ADuC7024/ADuC7025)

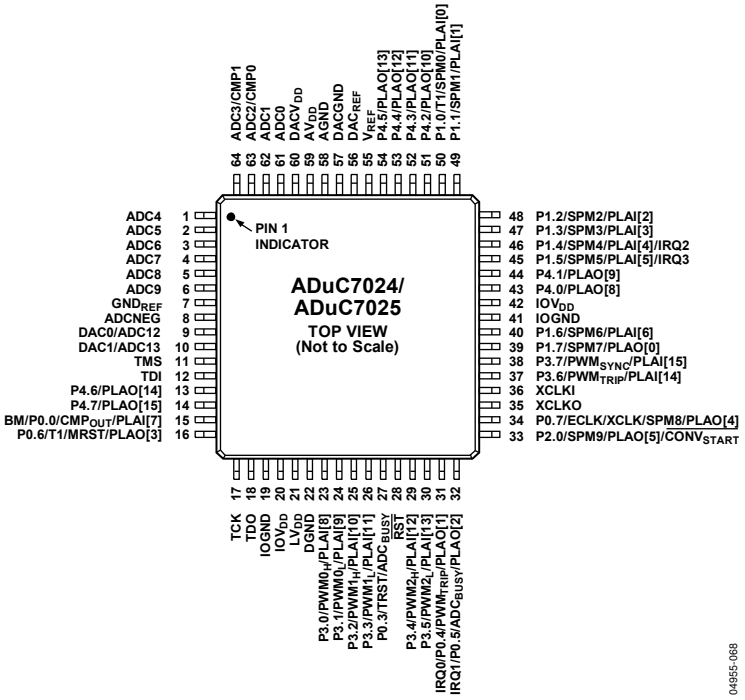


Figure 24. 64-Lead LQFP Pin Configuration (ADuC7024/ADuC7025)